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THIS TECHNOLOGY IS CURRENTLY NOT AVAILABLE FOR LICENSING

Tech ID: 33850



ADDITIONAL TECHNOLOGIES BY THESE INVENTORS

- ▶ Apodization Specific Peak Fitting In Charge Detection Mass Spectrometry
- ▶ Multiplex Charge Detection Mass Spectrometry
- ▶ Sequential Pass Express Charge Detection Mass Analyzer
- ▶ Ambient infrared laser ablation mass spectrometry (AIRLAB-MS) with plume capture by continuous flow solvent probe
- ▶ Aerosol Ionization For Charge Detection Mass Spectrometry Ion Mobility Analysis



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